

Supporting Information for

## Directional Electromagnetic Interference Shielding Based on Step-Wise Asymmetric Conductive Networks

Bai Xue<sup>1, 2</sup>, Yi Li<sup>1</sup>, Ziling Cheng<sup>1</sup>, Shengdu Yang<sup>1</sup>, Lan Xie<sup>1, 2, \*</sup>, Shuhao Qin<sup>2</sup>, Qiang Zheng<sup>1, 3, 4, \*</sup>

<sup>1</sup>Department of Polymer Materials and Engineering, College of Materials and Metallurgy, Guizhou University, Guiyang 550025, P. R. China

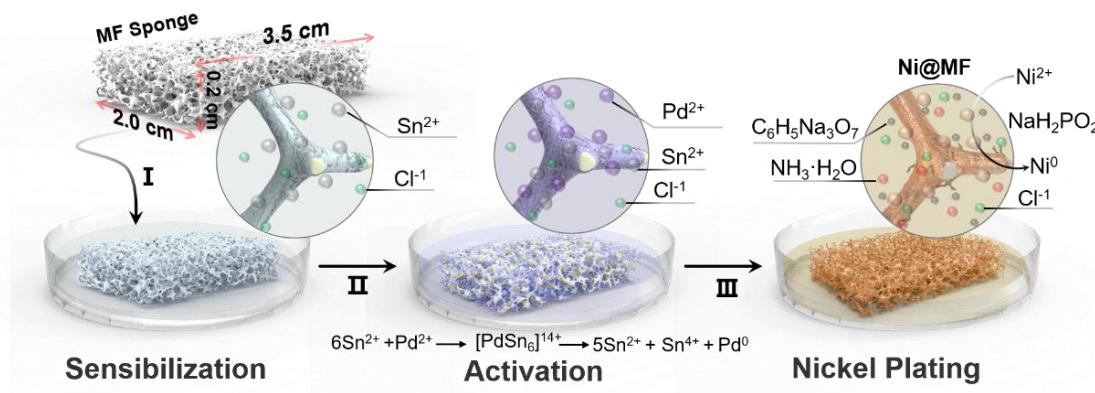
<sup>2</sup>National Engineering Research Center for Compounding and Modification of Polymer Materials; National and Local Joint Engineering Research Center for Functional Polymer Membrane Materials and Membrane Processes, Guiyang 550014, P. R. China

<sup>3</sup>College of Polymer Science and Engineering, Zhejiang University, Hangzhou 310027, P. R. China

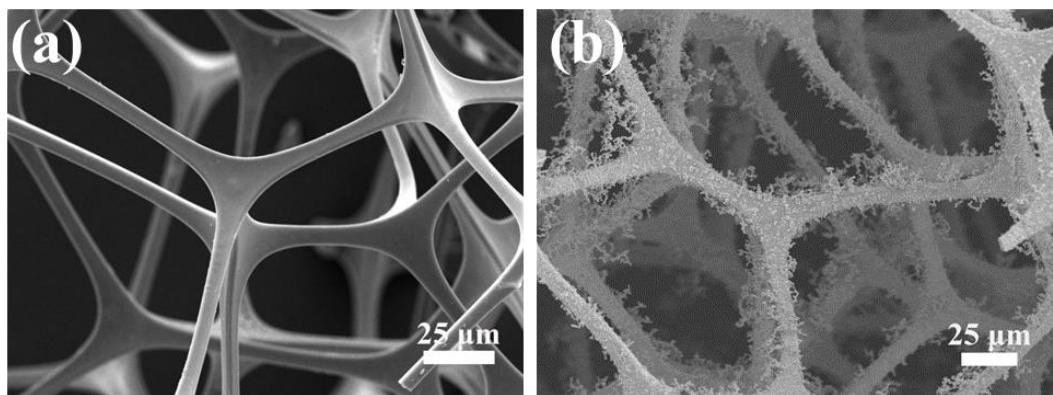
<sup>4</sup>College of Materials Science and Engineering, Taiyuan University of Technology, Taiyuan, 030024, P. R. China

\*Correspondence authors. E-mail: [mm.lanxie@gzu.edu.cn](mailto:mm.lanxie@gzu.edu.cn) (L. X.) or [zhengqiang@zju.edu.cn](mailto:zhengqiang@zju.edu.cn) (Q. Z.)

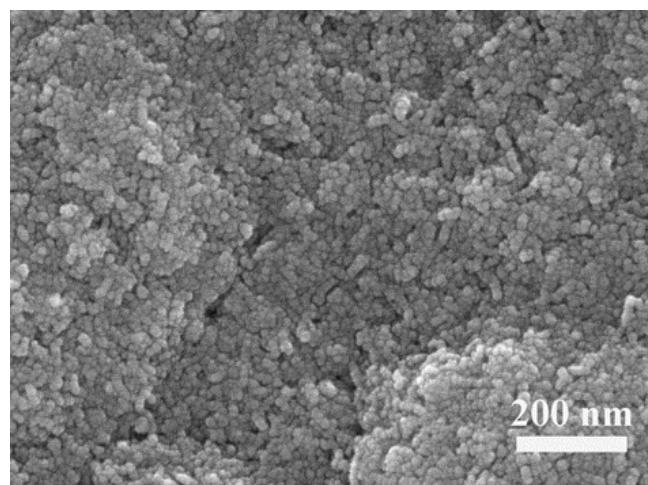
### Supplementary Figures and Table



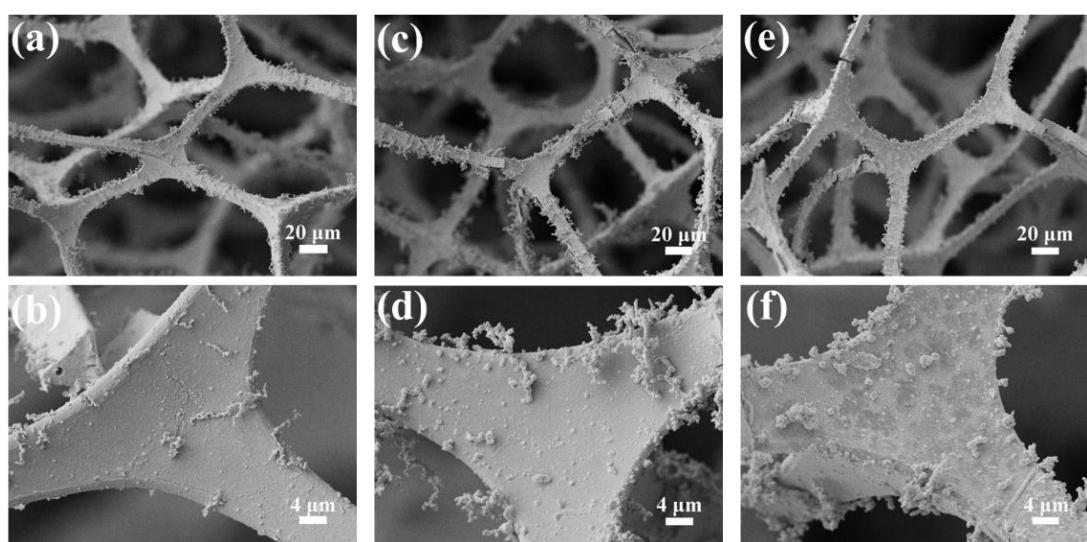
**Fig. S1** Schematic diagram for the syntheses of Ni@MF



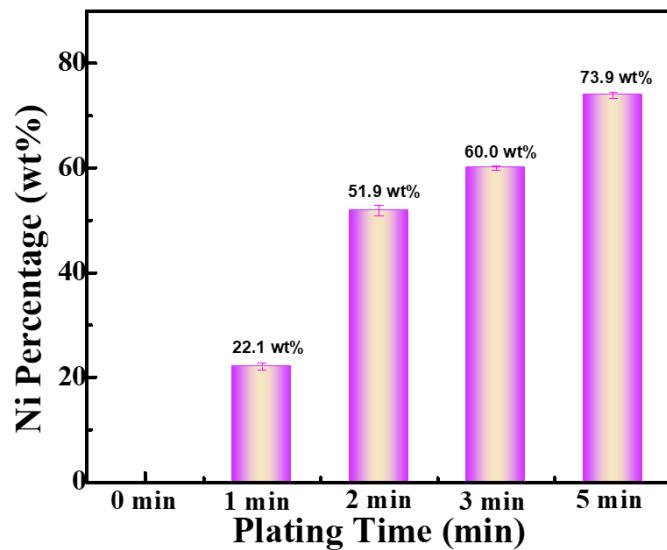
**Fig. S2** SEM images of (a) pure MF and (b) Ni@MF-5



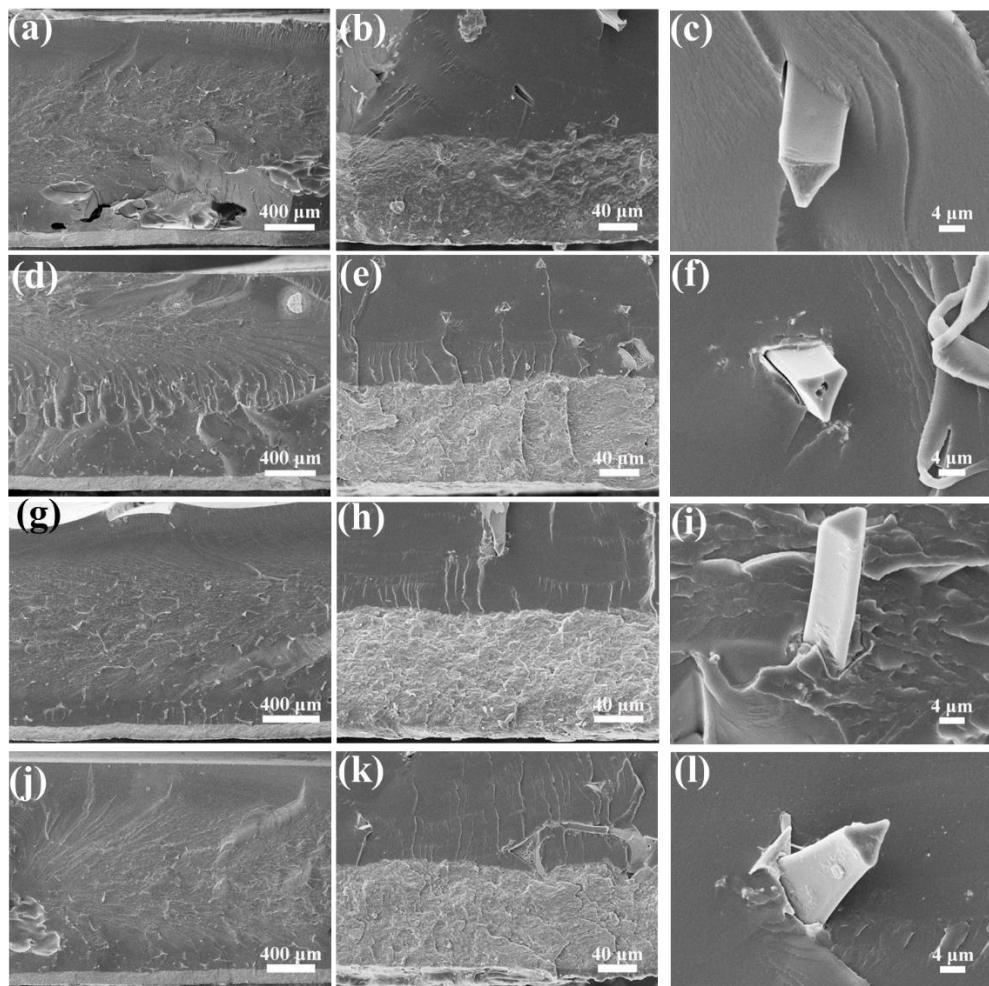
**Fig. S3** SEM image of Ni@MF-5 at high magnification



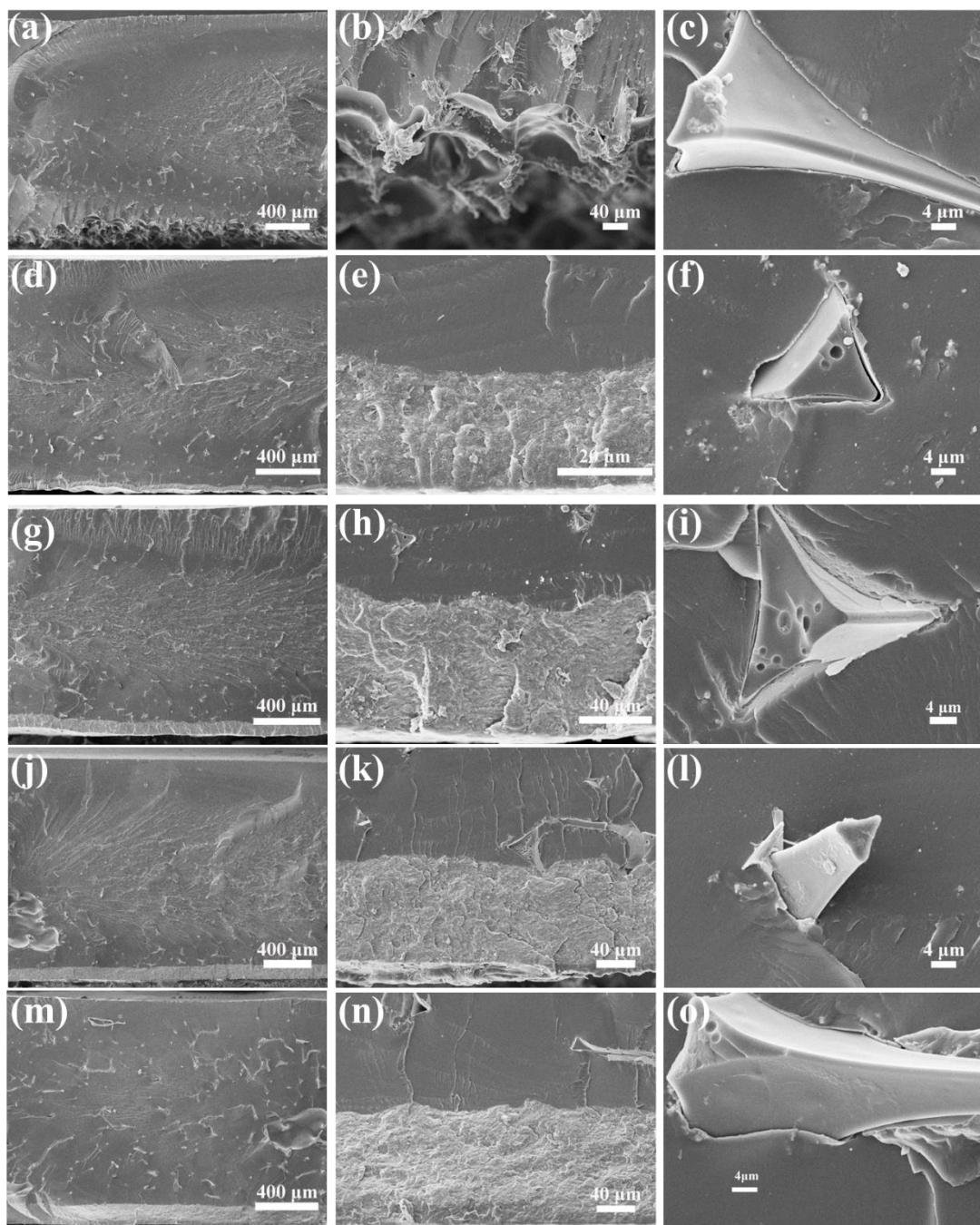
**Fig. S4** SEM images of Ni@MF with different plating time. SEM images of (a and b) Ni@MF-1, (c and d) Ni@MF-2, and (e and f) Ni@MF-3



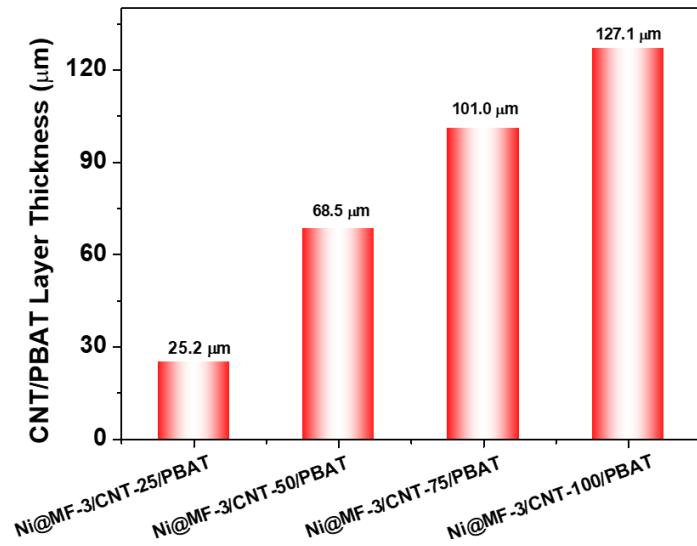
**Fig. S5** Ni percentage in Ni@MF as a function of plating time



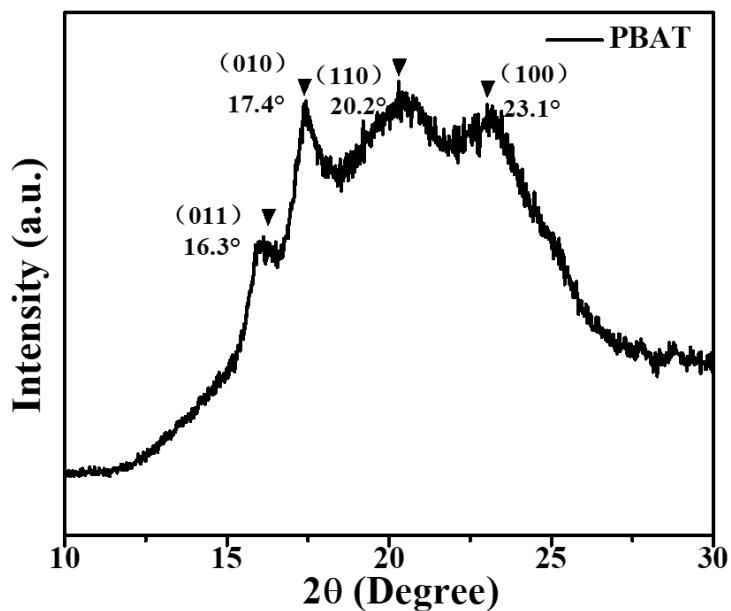
**Fig. S6 SEM images of Ni@MF/CNT-75/PBAT composites with different Ni-plating time.** SEM images of (a-c) MF/CNT-75/PBAT composites, (d-f) Ni@MF-1/CNT-75/PBAT composites, (g-i) Ni@MF-2/CNT-75/PBAT composites, and (j-l) Ni@MF-3/CNT-75/PBAT composites



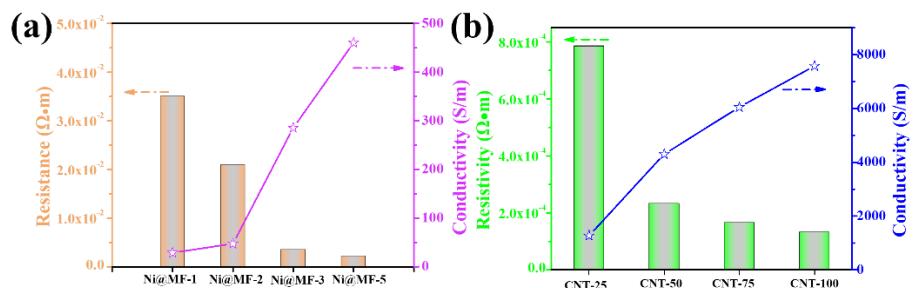
**Fig. S7 SEM images of Ni@MF-3/CNT/PBAT composites with different CNT thickness.** SEM images of (a-c) Ni@MF-3/PBAT composites, (d-f) Ni@MF-3/CNT-25/PBAT composites, (g-i) Ni@MF-3/CNT-50/PBAT composites, (j-l) Ni@MF-3/CNT-75/PBAT composites, and (m-o) Ni@MF-3/CNT-100/PBAT composites



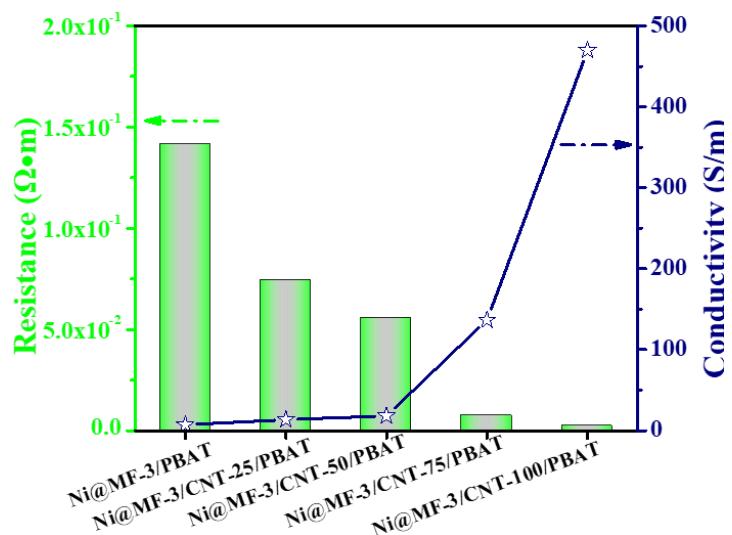
**Fig. S8** The thickness of CNT/PBAT layer in Ni@MF-3/CNT/PBAT composites with different CNT paper thickness



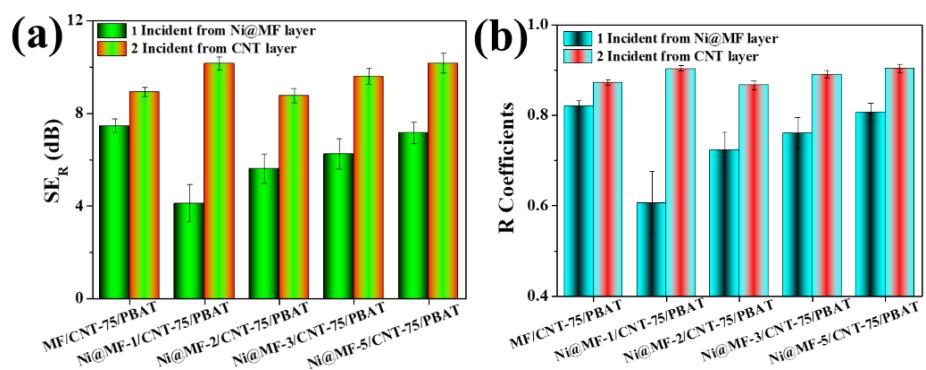
**Fig. S9** The magnified XRD pattern of PBAT in  $10\text{-}30^\circ$



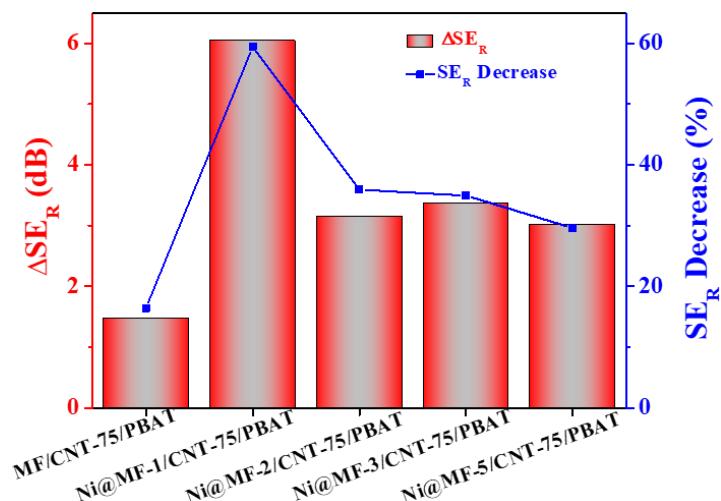
**Fig. S10** Resistance and conductivity of **(a)** Ni@MF with different plating time and **(b)** CNT papers with various thickness



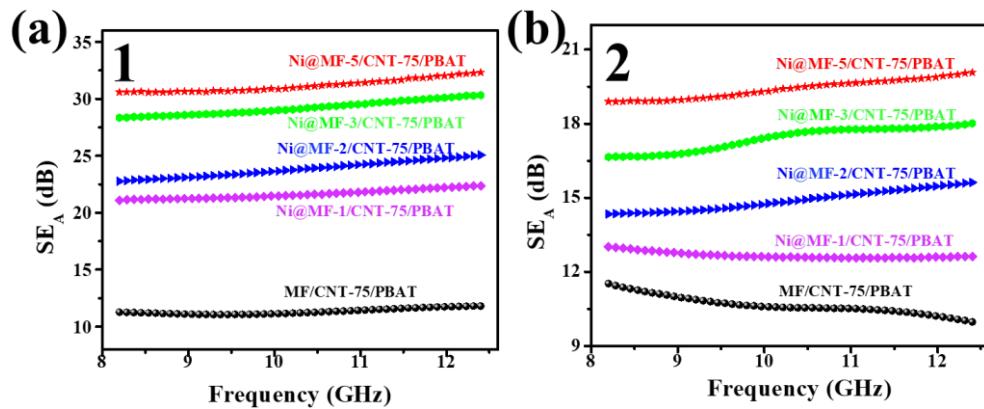
**Fig. S11** Bottom surface resistance and conductivity of Ni@MF/CNT/PBAT composites



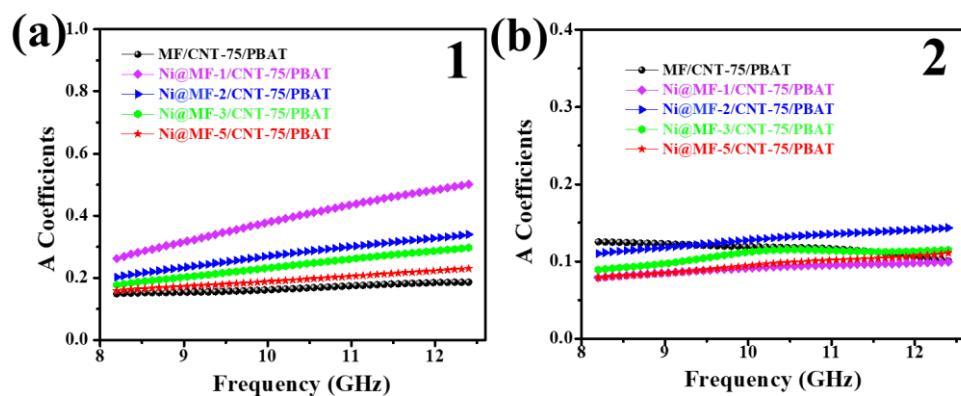
**Fig. S12** The average (a)  $SE_R$  and (b) R coefficients of Ni@MF/CNT-75/PBAT composites at different incident directions



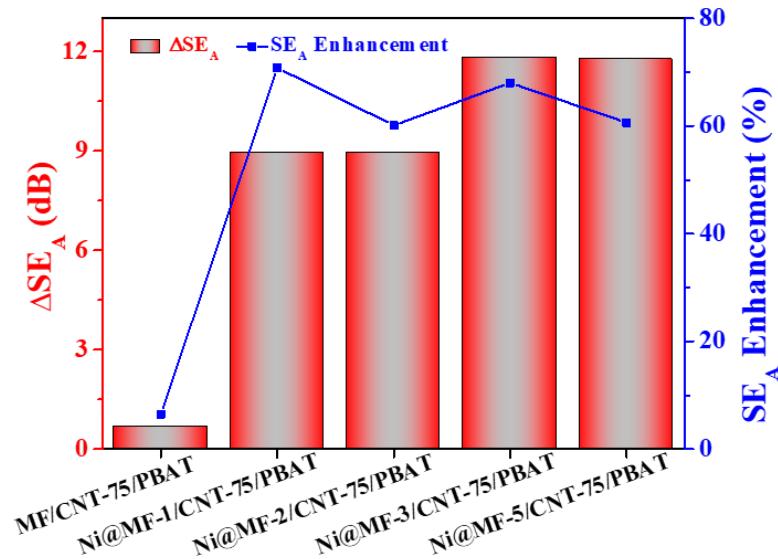
**Fig. S13**  $\Delta SE_R$  and  $SE_R$  enhancement of Ni@MF/CNT-75/PBAT composites at different incident directions



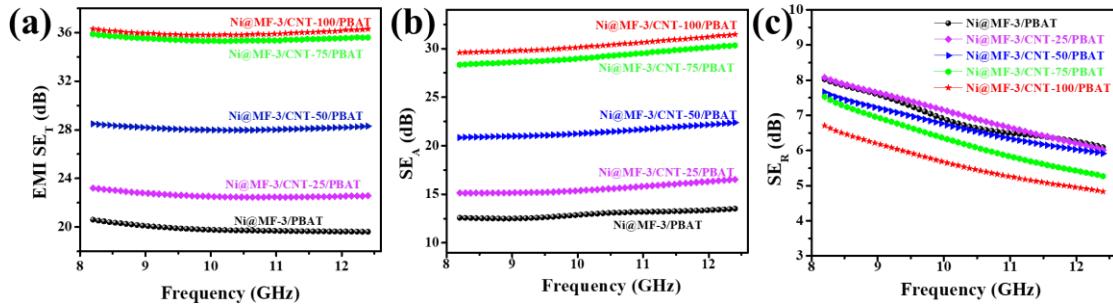
**Fig. S14** EMI  $SE_A$  in X-band for Ni@MF/CNT-75/PBAT composites, when the EM wave is incident from (a) Ni@MF layer and (b) CNT layer



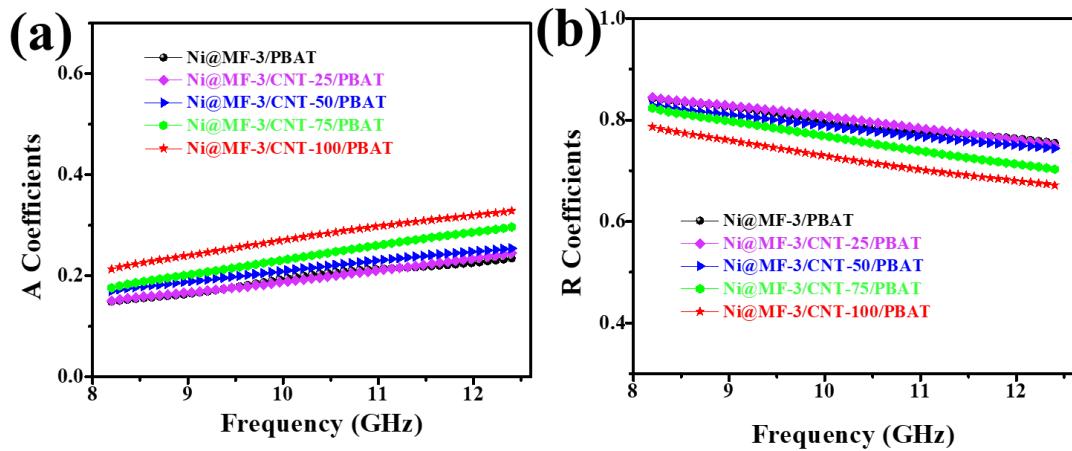
**Fig. S15** A coefficients in X-band for Ni@MF/CNT-75/PBAT composites, when the EM wave is incident from (a) Ni@MF layer and (b) CNT layer



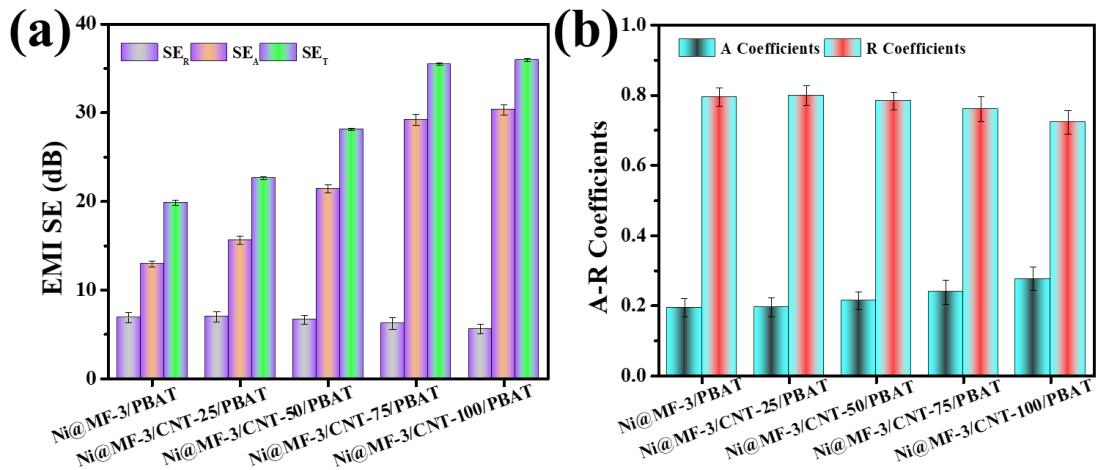
**Fig. S16**  $\Delta SE_A$  and  $SE_A$  enhancement of Ni@MF/CNT-75/PBAT composites at different incident directions



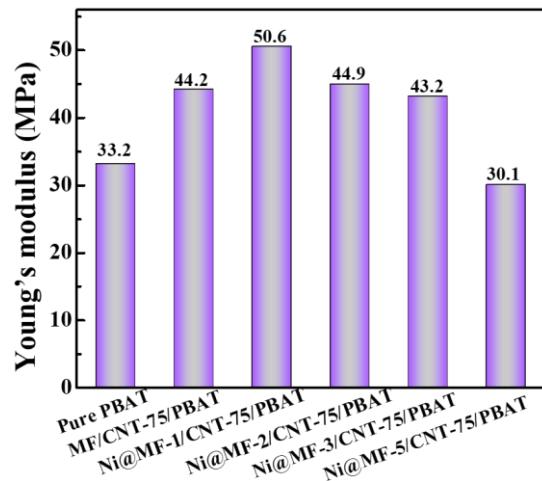
**Fig. S17** (a) EMI  $SE_T$ , (b)  $SE_A$ , and (c)  $SE_R$  in X-band for Ni@MF-3/CNT/PBAT composites, when the EM wave is incident from Ni@MF layer



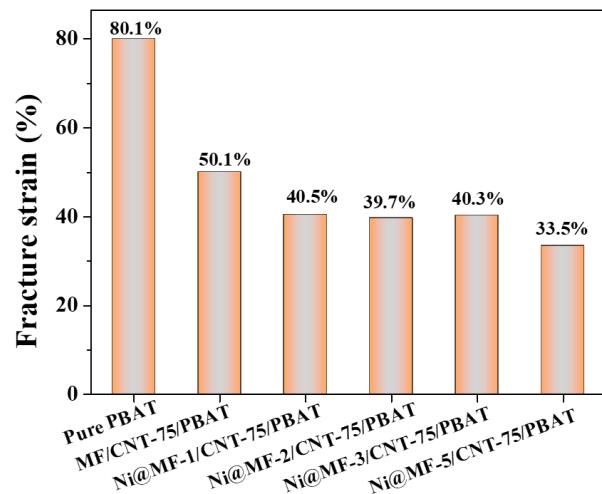
**Fig. S18** (a) A coefficients and (b) R coefficients in X-band for Ni@MF-3/CNT/PBAT composites, when the EM wave is incident from Ni@MF layer



**Fig. S19** (a) The average  $SE_T$ ,  $SE_A$ , and  $SE_R$ , and (b) average A-R coefficient of Ni@MF-3/CNT/PBAT composites with the incident EM wave from Ni@MF layer



**Fig. S20** The Young's modulus of pure PBAT and step-wise asymmetric Ni@MF/CNT-75/PBAT composites with different Ni plating time



**Fig. S21** The fracture strain of pure PBAT and step-wise asymmetric Ni@MF/CNT-75/PBAT composites with different Ni plating time

**Table S1** Atomic percentages of pure MF and Ni@MF-5

Sample	Elemental content (at%)			
	C 1s	O 1s	N 1s	Ni 2p
Pure MF	66.3	14.6	19.1	-
Ni@MF-5	53.3	13.3	17.4	15.6

**Movie S1** Practical application for directional EMI shielding